## Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10626596	SHEN ET AL.
Examiner	Art Unit

2617

SEARCHED						
Class		Subclass	Date	Examiner		
370	352		4/17/2008	GV		

GERMAN VIANA DI PRISCO

SEARCH NOTES					
Search Notes	Date	Examiner			
EAST Image and keyword search in USPAT, US-PGPUB, DERWENT,	4/17/2008	GV			
EPO, JPO, and IBM_TDB (see attached search strategy)					
Inventor name and Assignee search in PALM ExPO and EAST	4/17/2008	GV			
Consulted with Rafael Perez-Gutierrez	4/17/2008	GV			
EPO Database(http://ep.espacenet.com)	4/17/2008	GV			

INTERFERENCE SEARCH					
Class	Subclass	Date	Examiner		

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